

Fast 3D EM Simulation for Digital System Design

Ji Zheng
Apache Design Solutions



Outline

- **Digital system simulation requirement**
- **SiP, 3D IC and TSV**
- **3D fullwave EM solution progress review**
- **Chip modeling (from RTL to GDS) for system level EM analysis**

Scope and Challenge

- What is *System Level* EM simulation?
 - RTL to GDS
 - Chip, Package/SiP and PCB
- *Driven by*
 - Cost and margin
 - Risk mitigation and first time success
- *Challenges*
 - Accuracy and Capacity
 - Multi-domain physics
 - Next generation chip-package designs

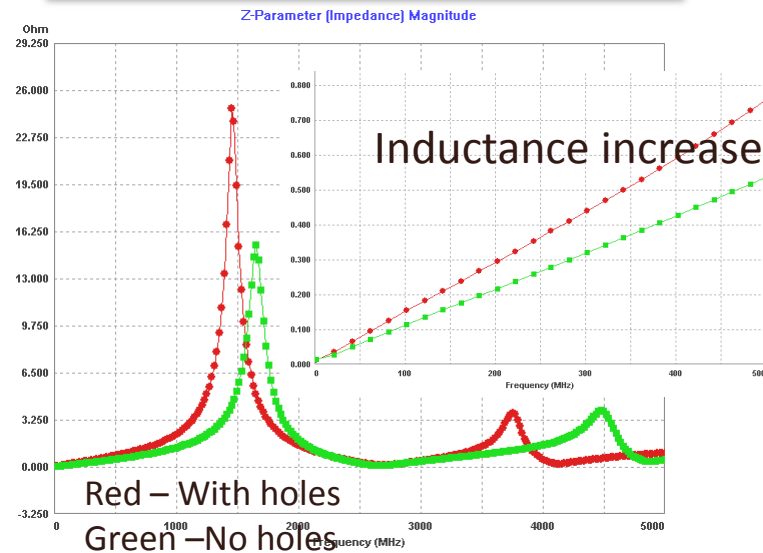
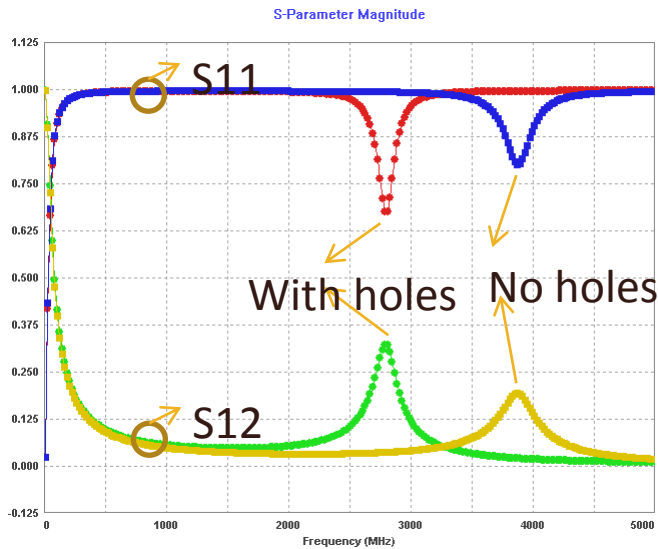
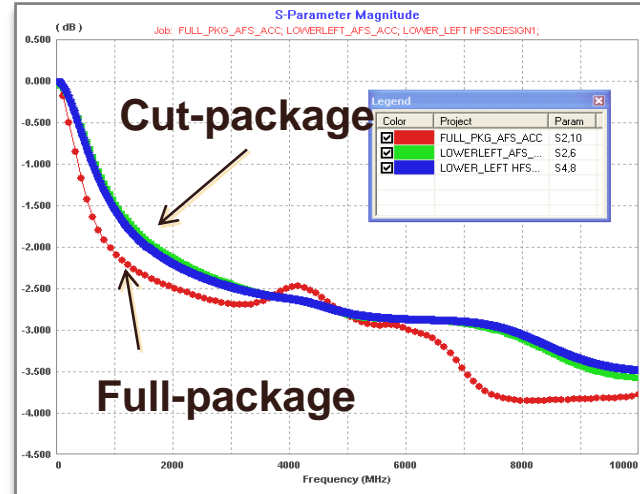
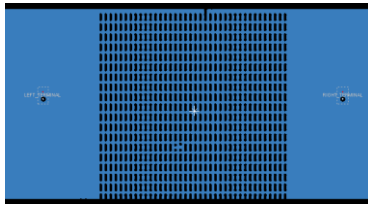
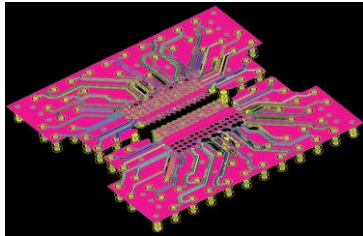
IC Technology Impact on Package/PCB

$$Z_{\text{target}} = (V_{\text{dd}} \times 0.05) / (I \times 50\%)$$

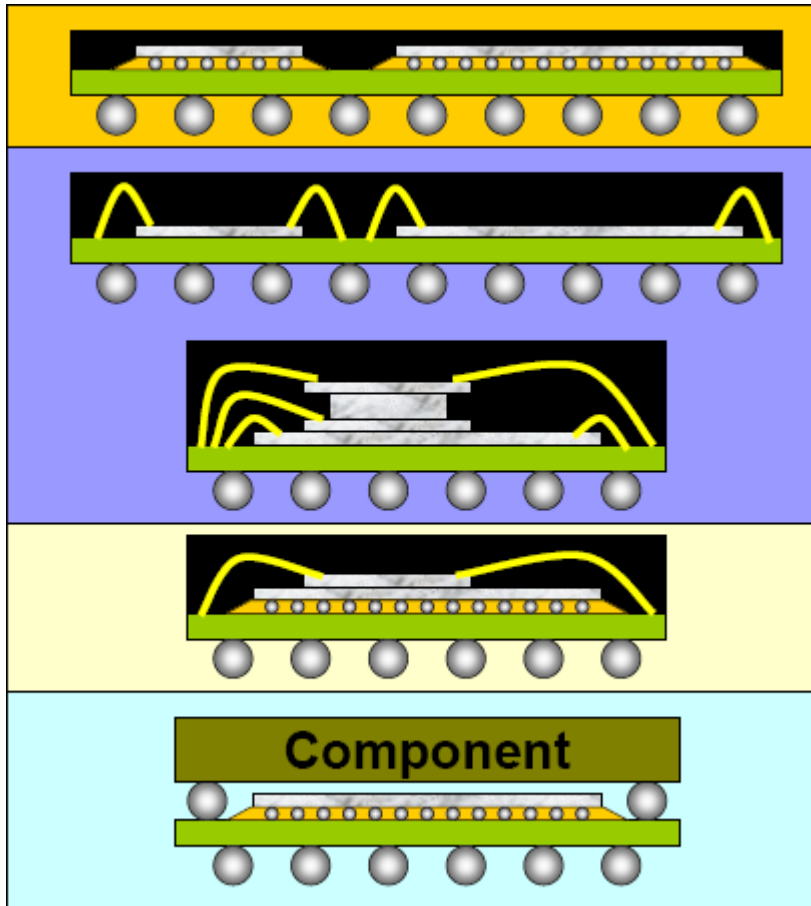
Year	Technology	Power (W)	Vdd (V)	Current (A)	Target Impedance (mΩ)
2004	90nm	84	1.2	70	1.7
2007	65nm	103	0.9	115	0.7
2010	45nm	119	0.6	198	0.3

System design margin is becoming Less and Less!

EM Accuracy Impact on Design Margin



Traditional SiP Configurations



● FC Side by side

● WB side by side

● Stacked WB

● Hybrid stack

● PoP stack

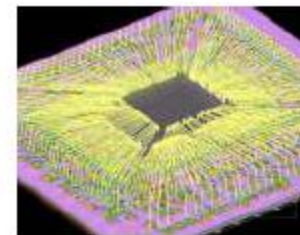
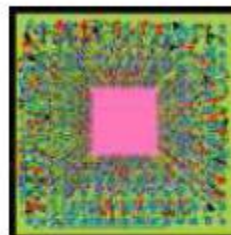
SiP Opportunities

SoC	SiP
Single tech node	Multiple tech node
All IP's ported to same technology node	Mix of IP's in diff technology nodes
Horizontal partitioning	Horizontal & Vertical partitioning

SiP Design Flow: Reference Flow 10.0

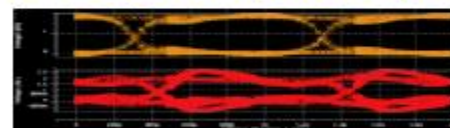
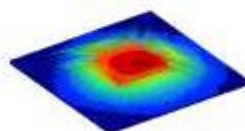
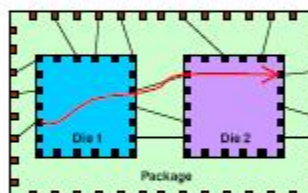
- **Basic Implementation**

- SiP Elec Design/Connectivity
- SiP Package Physical Design



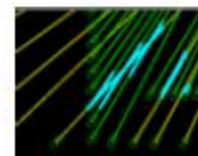
- **Analysis**

- SiP Package Electrical Extraction
- SiP Static Timing Analysis (STA)
- SiP IR Drop
- SiP Signal Integrity (SI) & Simultaneous Switching Noise (SSN)
- SiP Thermal

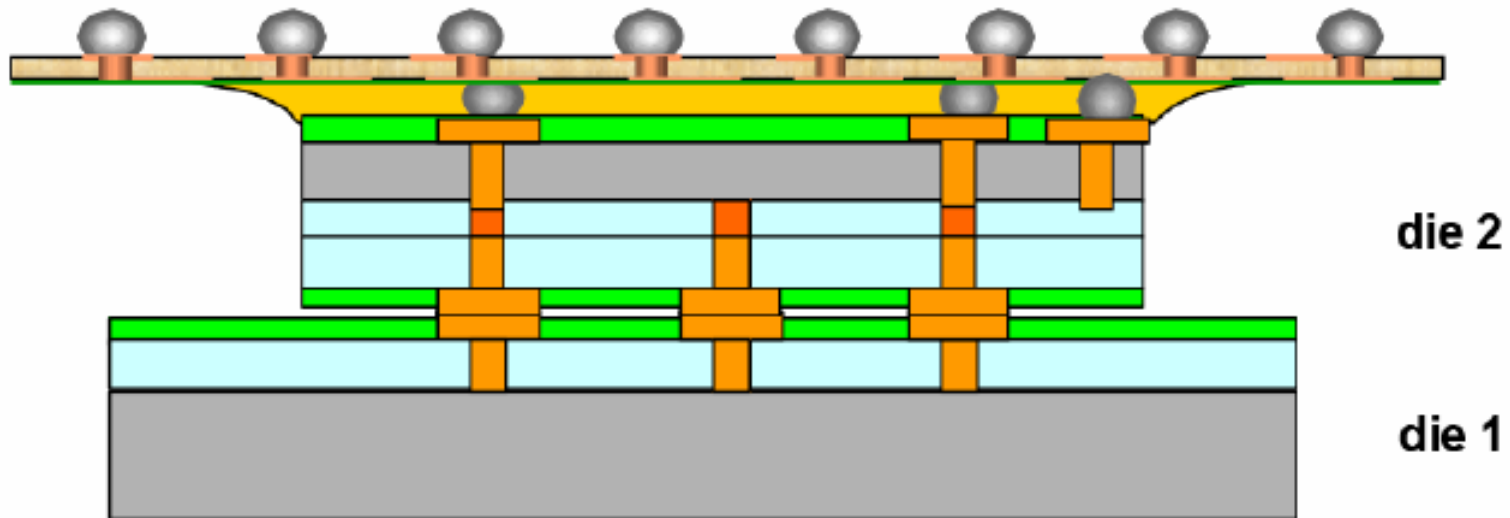


- **Verification**

- SiP Design Rule Check (DRC)
- SiP Layout Versus Schematic (LVS)



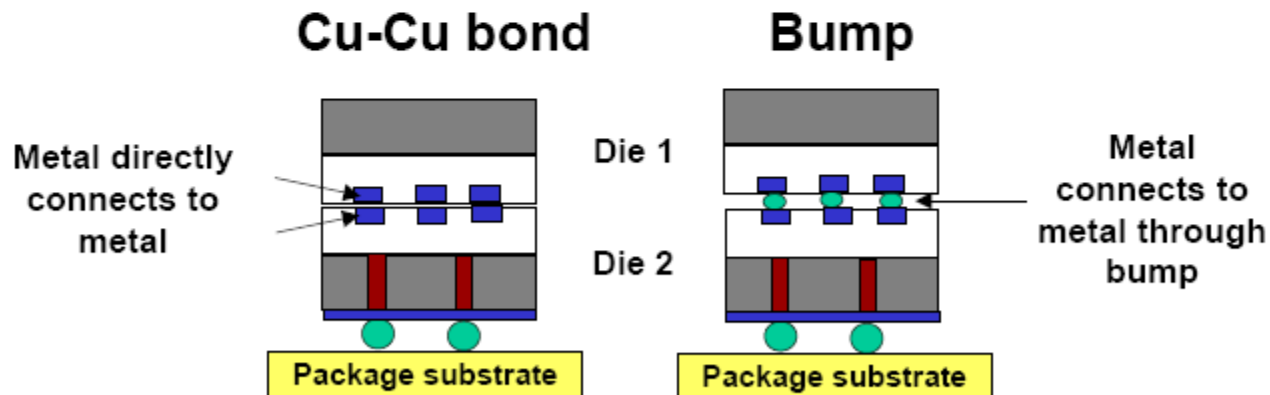
3D Stacking with TSV



Die-to-die Connection

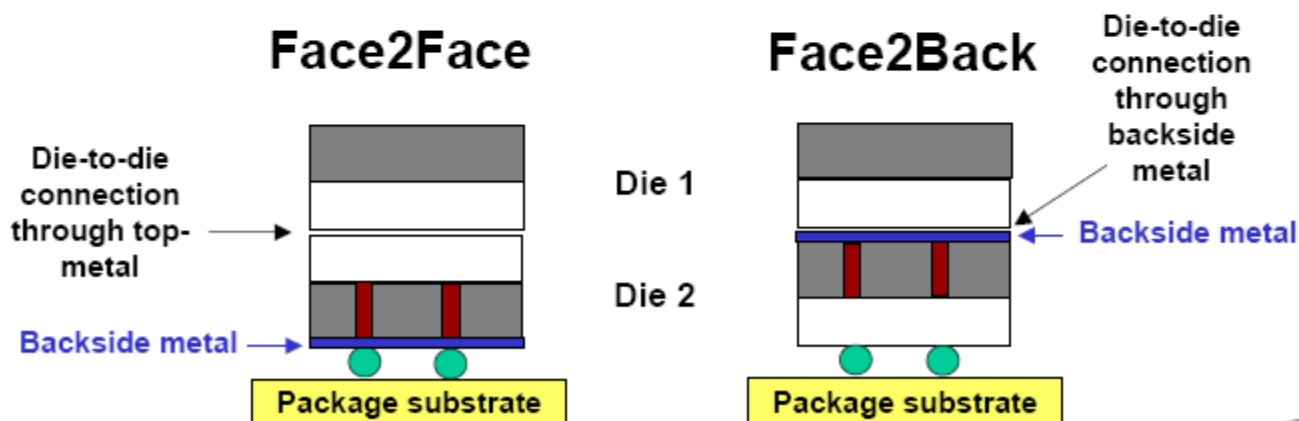
- **Cu-Cu bond or Bump**

- **Cu-Cu bond:** Top-metal from each die touch directly to create connectivity
- **Bump:** Top-metal from each die connected through bump as in standard bump process.



Stacking Schemes

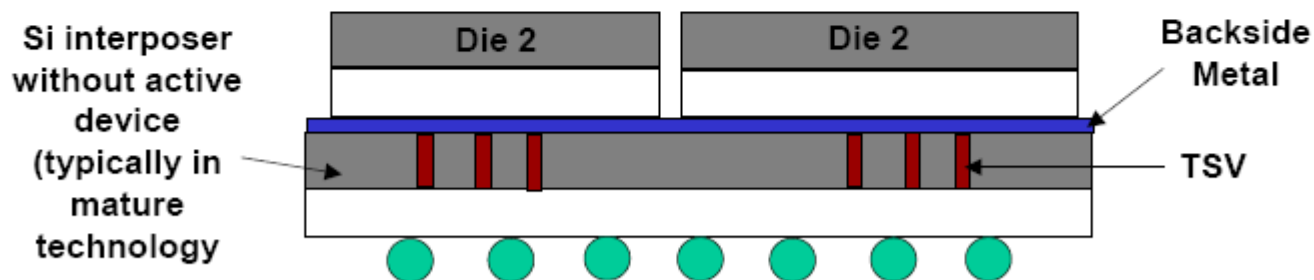
- **Face2Face or Face2Back**
 - **Face2Face:** Top-metal of two dice connected to each other and has package bump on backside
 - **Face2Back:** Top-metal of first die connected to backside metal of second die and has package bump on front-side



Silicon Interposer using TSV

- Alternative use of TSV

- TSV technology provides opportunities beyond 3D stacking
- TSV can be used to implement Si-Interposer that replaces package substrate in traditional SiP's
- Advantages in lower parasitics and denser routing



3D IC Benefits

- **Form-factor**
 - Same as SoC without SoC complexity
- **Speed**
 - TSV RC in same order as chip metal
 - Die interconnect as opposed to off-chip interconnect
- **Power**
 - IO power reduced

3D IC Design and Analysis Challenges

- **Die-package co-design is a must**
- **3D electromagnetic simulation necessarily beyond package and PCB**

System Level EM Simulation

- **Complexity and size of the design requires large capacity and high efficiency**
- **Multiscale geometry usually leads to worse conditioning of the final matrix system**
- **Broadband solution requires the EM engine to work seamless from DC to multi-giga Hertz**
- **Whole system analysis requires the bi-directional link between EM model and circuit components**

Progress on FEM

- **Domain decomposition method**
 - Various forms
 - Frequency domain and time domain
 - Parallelization
- **Multi-grid method**
- **Layered finite element reduction recovery method**

Progress on MoM

- **Improve electric field integral equation (EFIE) for better conditioning over broadband**
 - Calderon multiplicative preconditioner leverages the Calderon identity to obtain a well conditioned matrix
 - Augmented electric field integral equation (AEFIE) in a generalized saddle point form is a simple remedy for the low-frequency break down of EFIE
 - Current and charge integral equation (CCIE) constructs a sophisticated second kind integral equation to improve the conditioning
 - Equivalence principle algorithm (EPA) is an integral equation based domain decomposition method for multiscale structure

Progress on MoM

- **Reduce dense matrix operation towards linear complexity**
 - Multilevel fast multipole algorithm (MLFMA) factorizes the Green's function based on the addition theorem
 - FFT based method utilizes the block Toeplitz structure of the impedance matrix of a regular grid
 - Fast QR method compresses the well-separated impedance matrix blocks
 - Adaptive cross approximation (ACA) is a rank-revealing LU decomposition without the need of computing all the matrix elements
 - H2 matrix creates block partitioning based on a cluster tree and approximates the integral operator kernel with polynomial interpolation

Define Next Generation Fast 3D Solver

- Full package and PCB capacity
- DC to 10's GHz fullwave accuracy
- Native multi-core and multi-processor
- Robust co-simulation with circuits
- Handle multi-scale geometry

Co-Analysis

EM Source

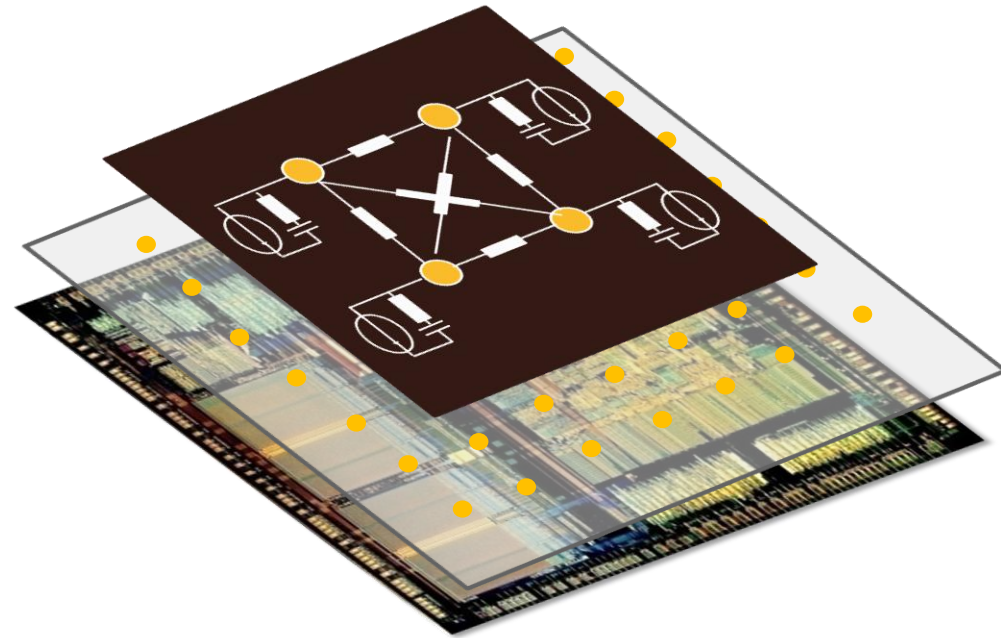
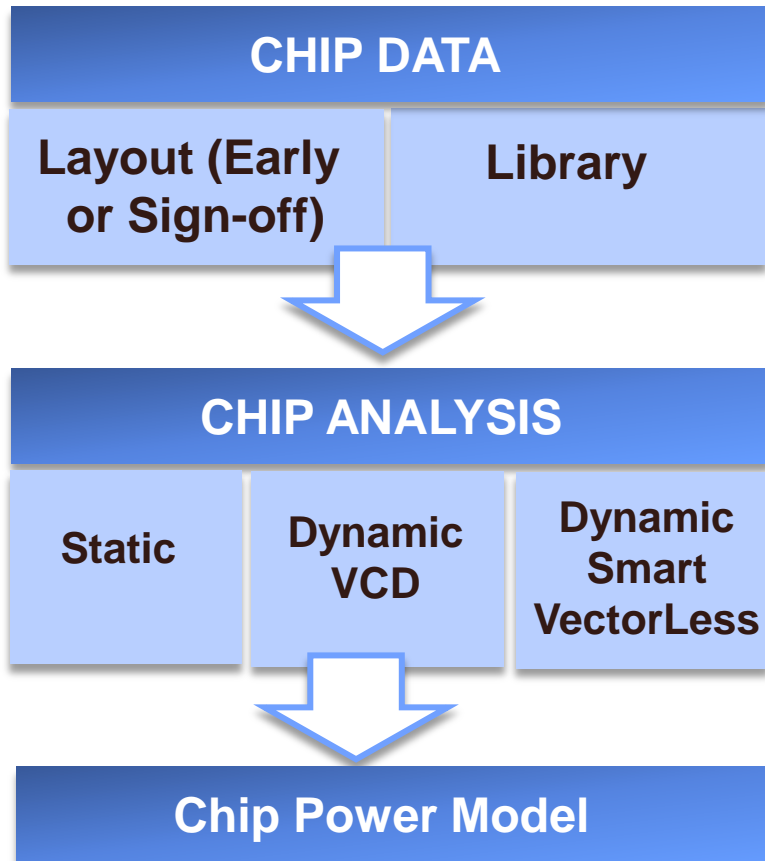
- On-die device switching
- On-die substrate coupling
- IO simultaneous switching
- On-die core to IO coupling

EM Channel

- Package/PCB global power ground network
- Package/PCB power to signal coupling
- Signal return path discontinuity
- Radiation from traces, wires, vias and edges

Chip Power Model

Power Delivery Network Analysis & Optimization



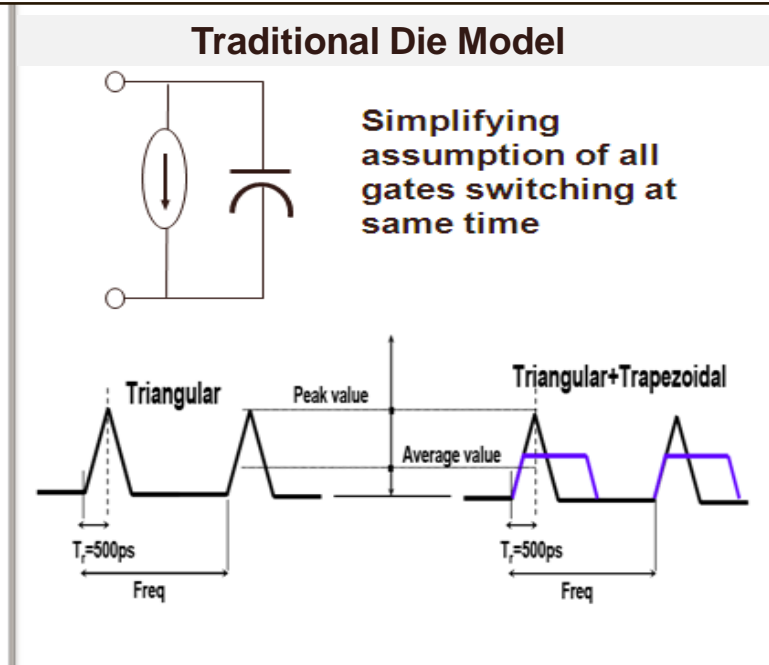
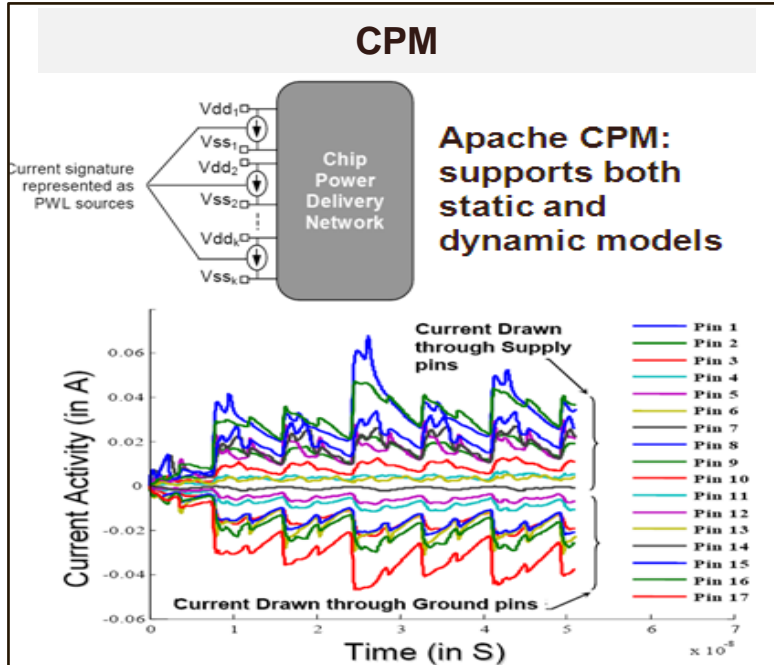
Modes

- Static (I_{avg} , R)
- Frequency domain (RLC)
- Time-domain ($I(t)$, RLC)

Chip Power Model

Power Delivery Network Analysis & Optimization

Switching Current



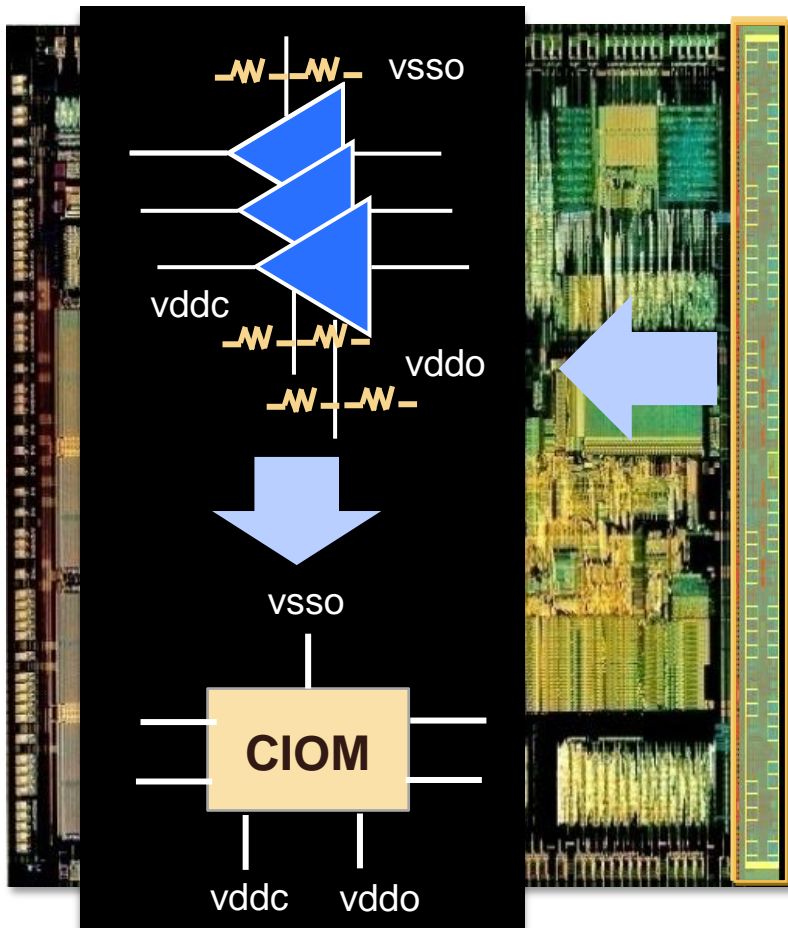
Die Parasitics

CPM includes all die parasitics

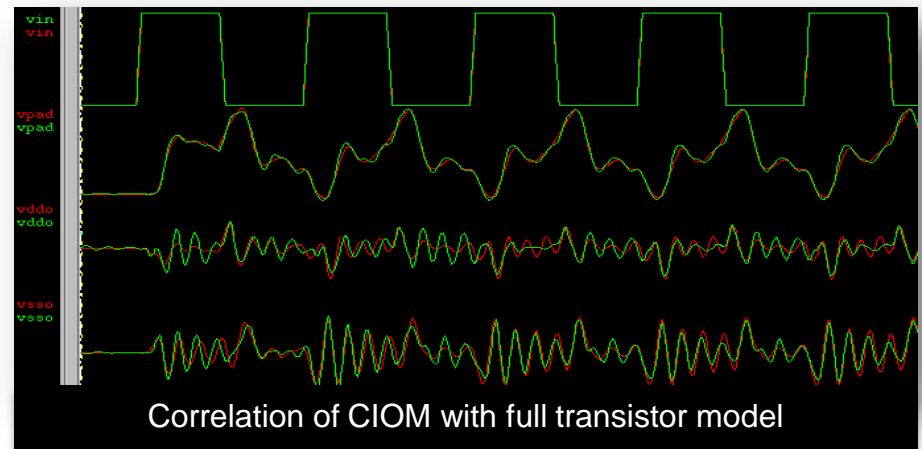
- Power-grid RLC
- Intrinsic De-cap
- Intentional De-cap
- Instance Load Capacitance
- Well Capacitance

Estimated Cdie
Missing Rdie, Ldie

Chip IO Model – IO Behavioral Modeling Signal Integrity Analysis & Optimization



Models Switching behavior & PG parasitics
Enables IP protection

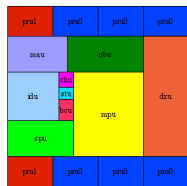
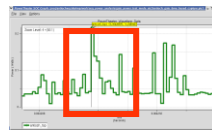


RTL Modeling for System EM Analysis

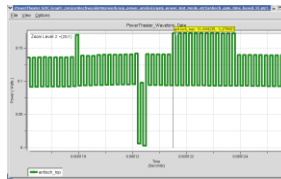


RTL design and IP models

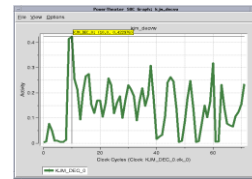
POWER THEATER



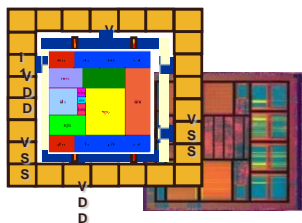
Block Average Power or Current



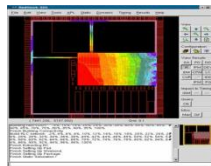
Cycle-average power vs. time



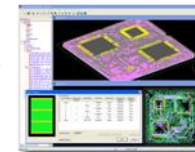
Cycle-average activity vs. time



Power Grid + Floorplan SoC Layout

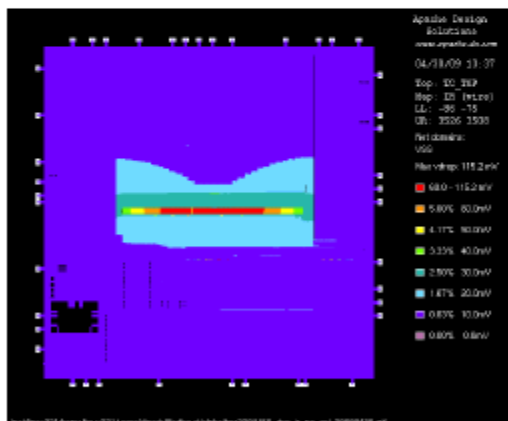


Targeted vectorless DVD

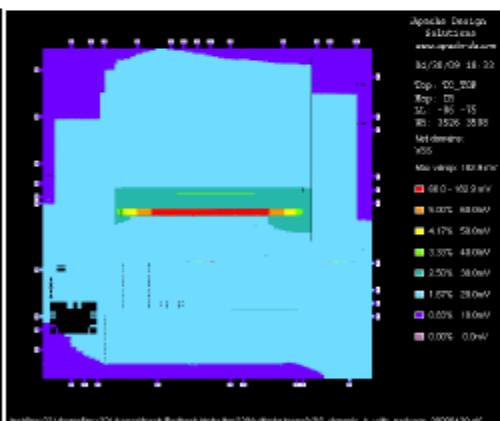


On-die PDN and Pkg/PCB Signoff

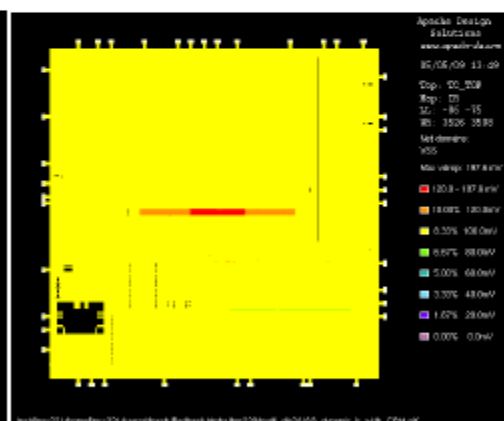
SiP IR Drop Example



Logic DVD without Package
DVD Peak = 115.2 mV
DVD Avg. = ~ 2 %



Logic DVD with Package
DVD Peak = 182.9 mV
DVD Avg. = ~ 2 - 3%



SRAM DVD with Package + ARM CPM
DVD Peak = 197.6 mV
DVD Avg. >= 8.3 %